



Bonded Interfaces for High-Temperature Power Electronics

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This presentation does not contain any proprietary, confidential, or otherwise restricted information.

Agenda

- NREL Overview
- Background & Approach
- Bonded Interfaces Reliability
 - 150°C
 - 200°C
- Thermomechanical Modeling
 - Parametric study of a power module
 - Demonstration using ANSYS
- Challenges and Opportunities
- Summary

Department of Energy Laboratories

Office of Science Laboratories

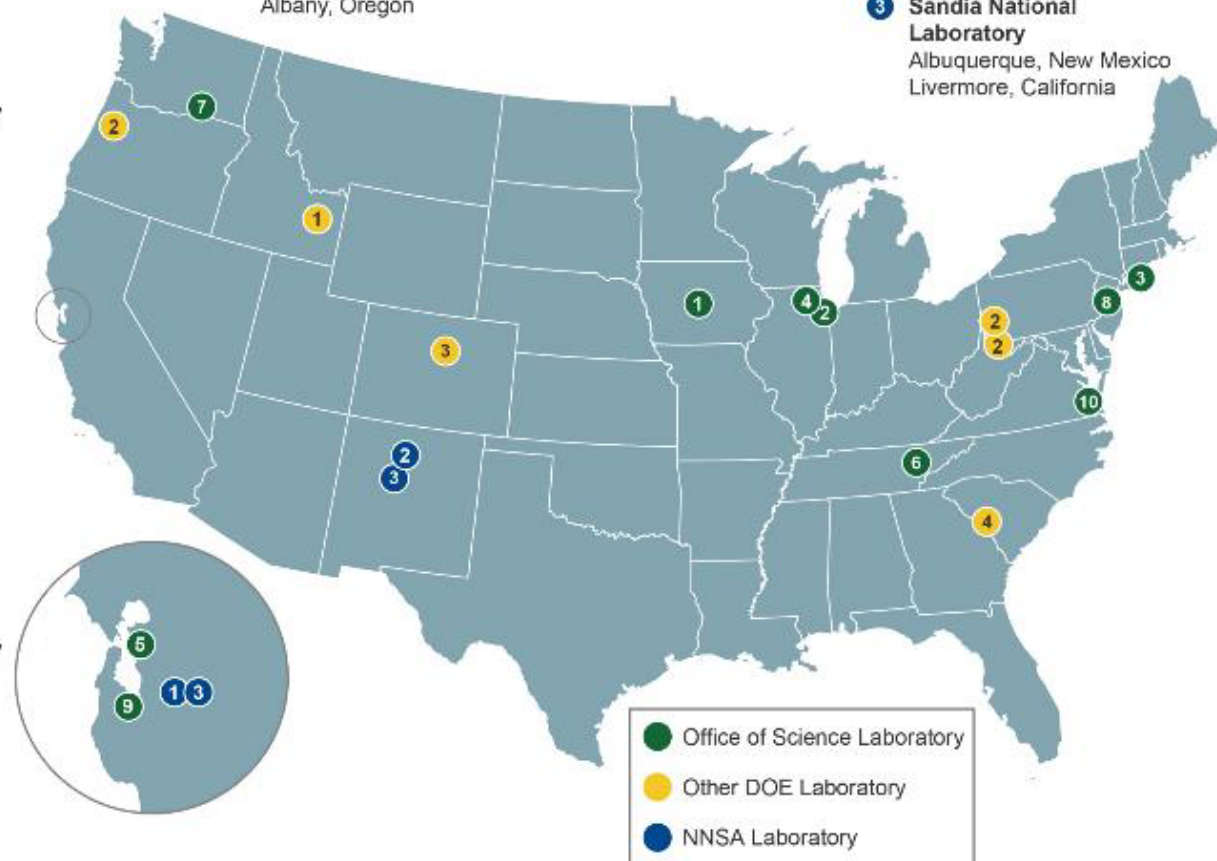
- 1 Ames Laboratory
Ames, Iowa
- 2 Argonne National Laboratory
Argonne, Illinois
- 3 Brookhaven National Laboratory
Upton, New York
- 4 Fermi National Accelerator Laboratory
Batavia, Illinois
- 5 Lawrence Berkeley National Laboratory
Berkeley, California
- 6 Oak Ridge National Laboratory
Oak Ridge, Tennessee
- 7 Pacific Northwest National Laboratory
Richland, Washington
- 8 Princeton Plasma Physics Laboratory
Princeton, New Jersey
- 9 SLAC National Accelerator Laboratory
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- 10 Thomas Jefferson National Accelerator Facility
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NNSA Laboratories

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Livermore, California
- 2 Los Alamos National Laboratory
Los Alamos, New Mexico
- 3 Sandia National Laboratory
Albuquerque, New Mexico
Livermore, California



National Renewable Energy Laboratory



Leading clean-energy
innovation for 44
years



2,500 employees
with world-class
facilities



Campus is a living
model of sustainable
energy



Owned by the
Department of
Energy (DOE)



Operated by the
Alliance for
Sustainable Energy

Scope of NREL Mission

Sustainable Transportation

Vehicle Technologies

Hydrogen

Biofuels

Energy Productivity

Residential Buildings

Commercial Buildings

Manufacturing

Renewable Electricity

Solar

Wind

Water: Marine Hydrokinetics

Geothermal

Systems Integration

Grid Integration of Clean Energy

Distributed Energy Systems

Batteries and Thermal Storage

Energy Analysis

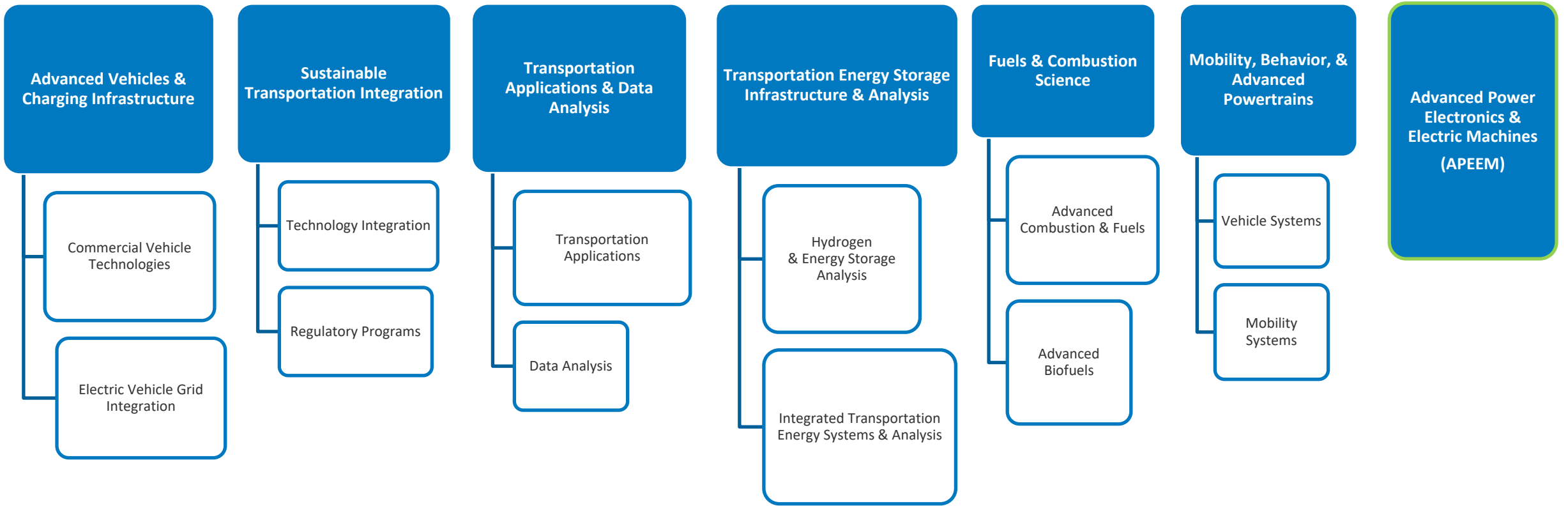
Partnerships

Private Industry

Federal Agencies

State/Local Government

International

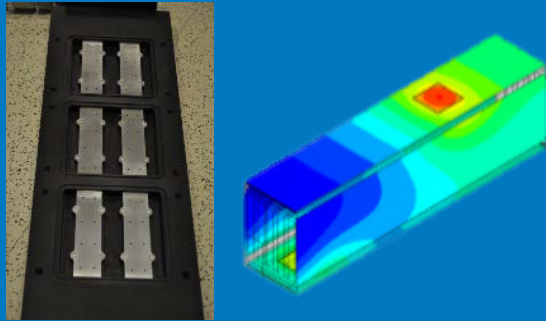


Center for Integrated Mobility Sciences (CIMS)

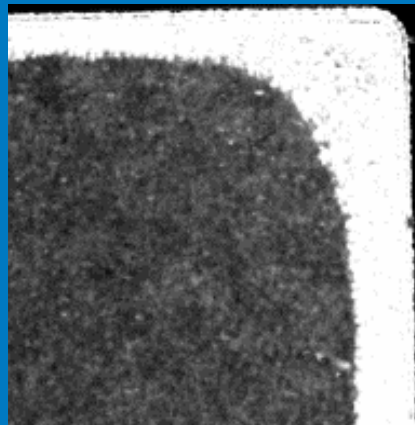
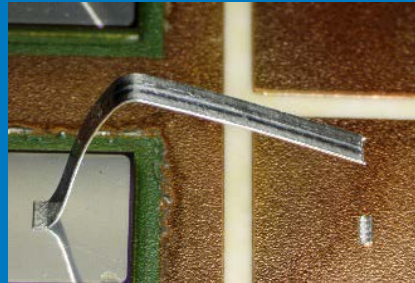
APEEM Group: Twelve (12) staff members involved in thermal, electro-thermal, thermomechanical, and reliability research activities.

APEEM Group Focus Areas

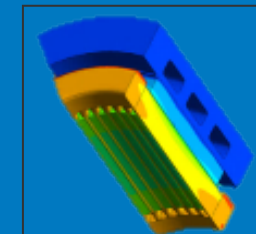
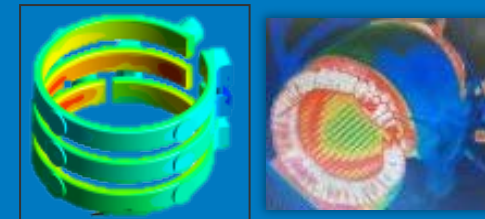
Power Electronics Thermal Management



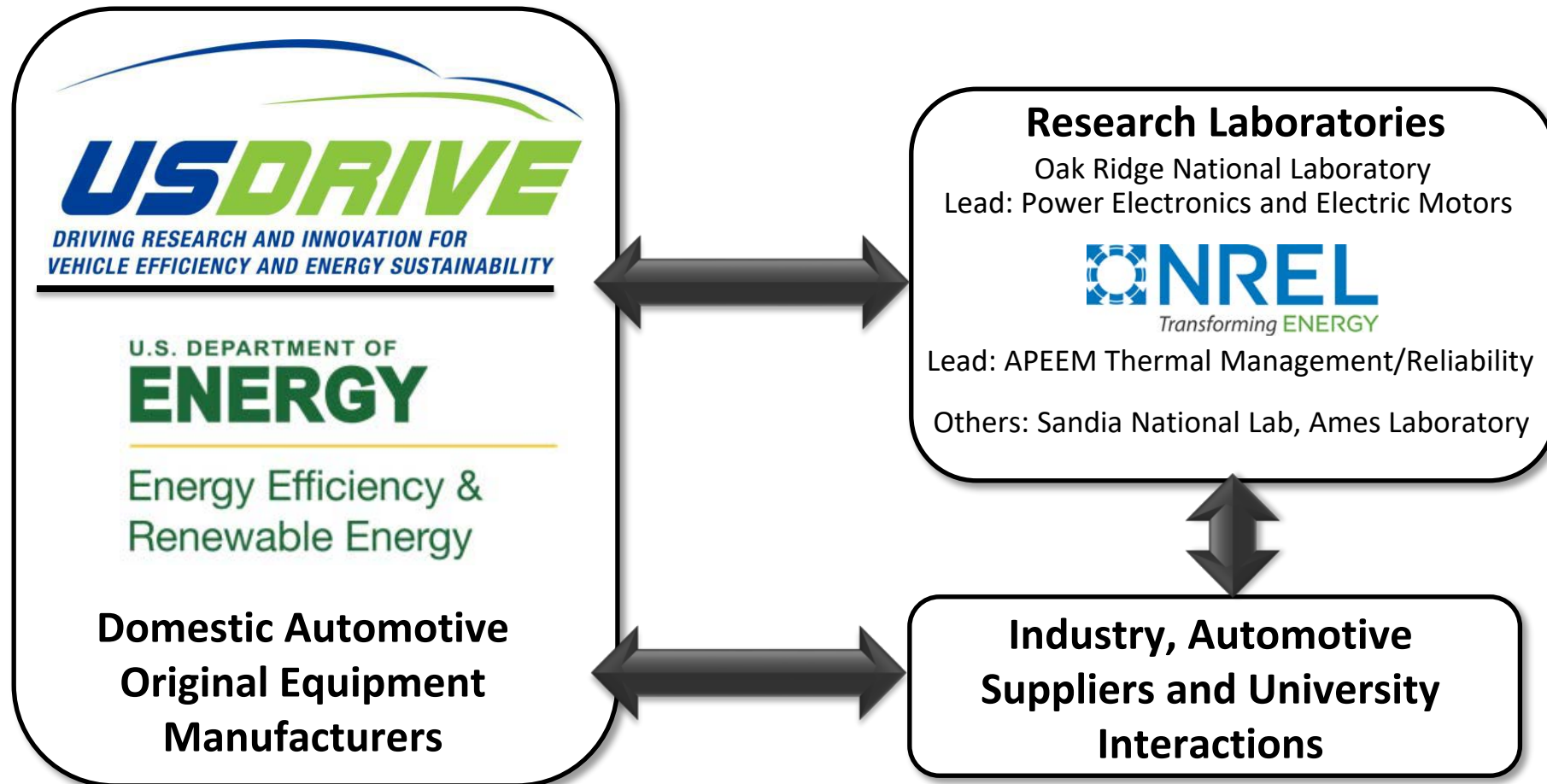
Advanced Packaging Designs and Reliability



Electric Motor Thermal Management



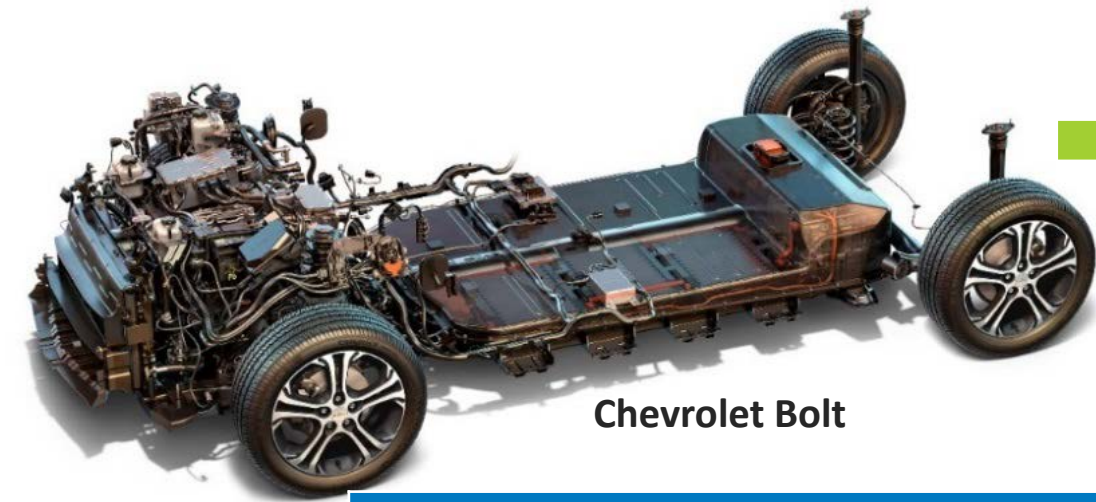
DOE Electric Drive Technologies (EDT) Program



Background & Approach

Research Pathway for Electric-Drive Vehicle Electrification

Roadmap defines the pathway to 2025 targets



Chevrolet Bolt



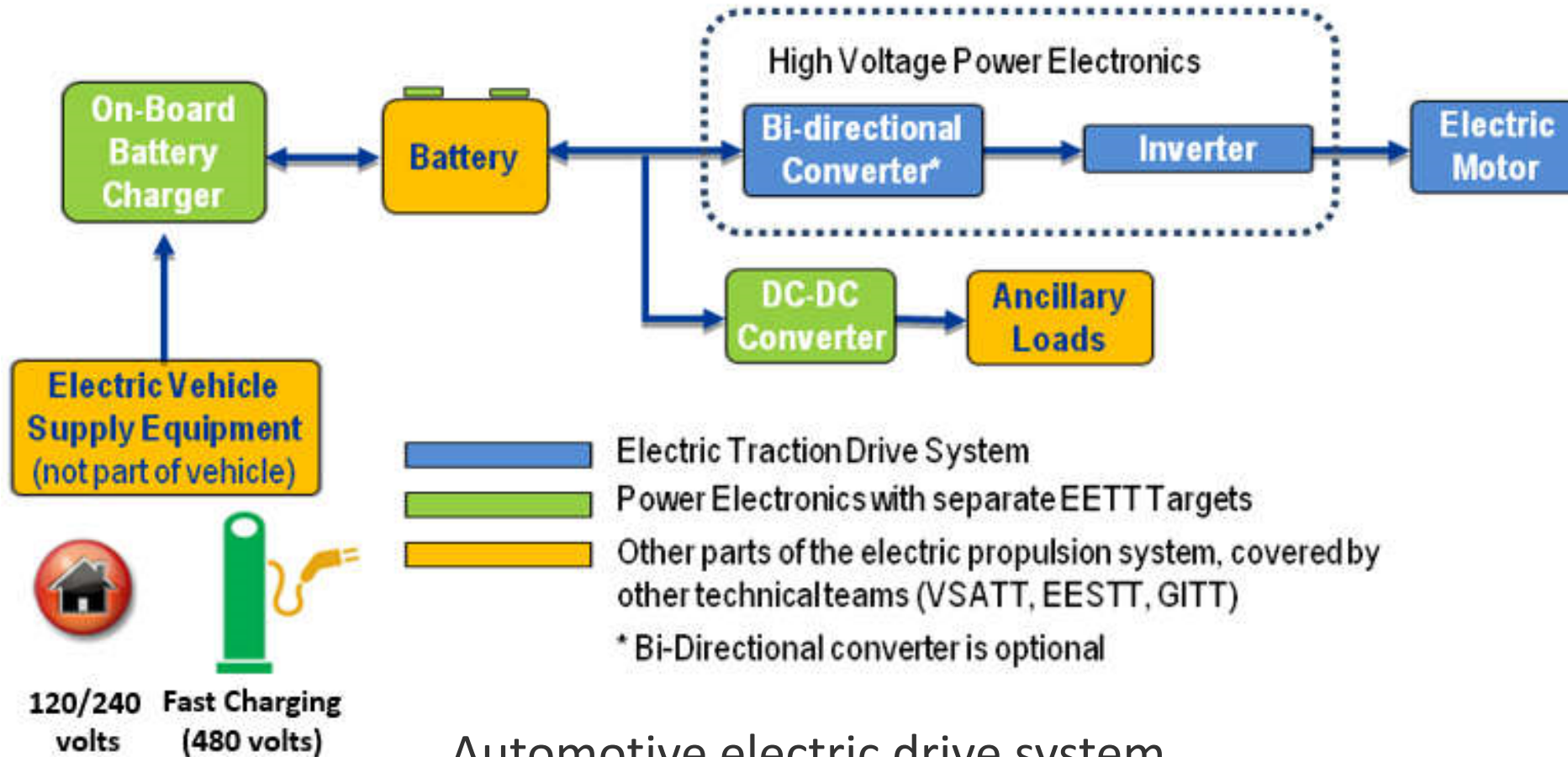
Future Mobility Design Concept

2025 Targets

Cost	\$6/kW (50% reduction)
Power Density	33 kW/L (850% increase)
Power Level	100 kW
Reliability/Lifetime	300,000 miles (100% increase)

Source: Electrical and Electronics Technical Team Roadmap, <https://www.energy.gov/sites/prod/files/2017/11/f39/EETT%20Roadmap%2010-27-17.pdf>.

Electric Drive System



Automotive electric drive system

- **Cost**
- **Power density**
- **Reliability**

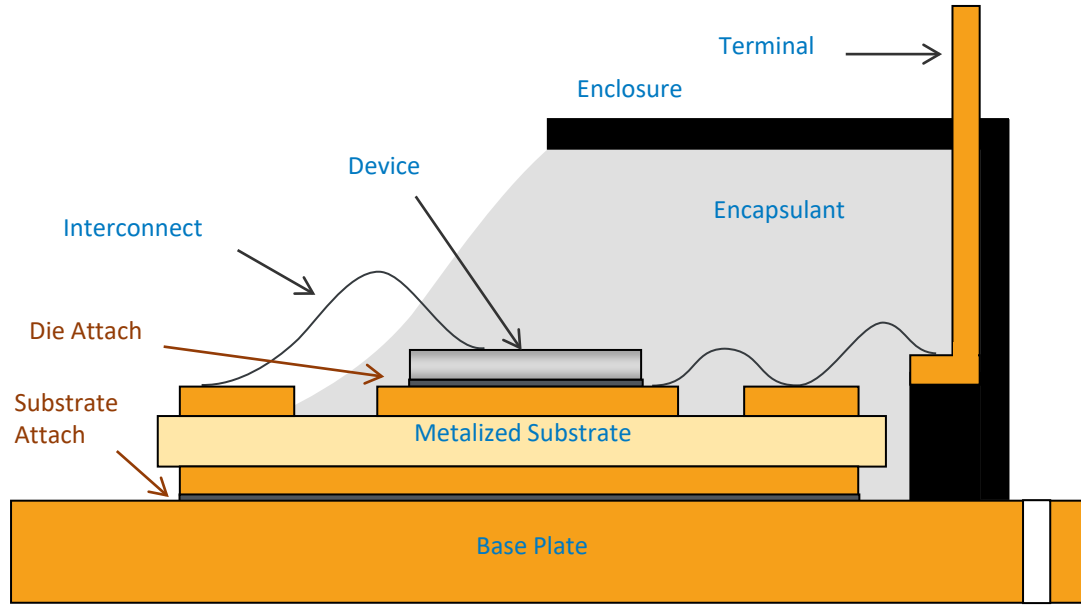
Schematic from 2017 Electrical and Electronics Technical Team (EETT) Roadmap

VSATT – Vehicle Systems Analysis Tech Team

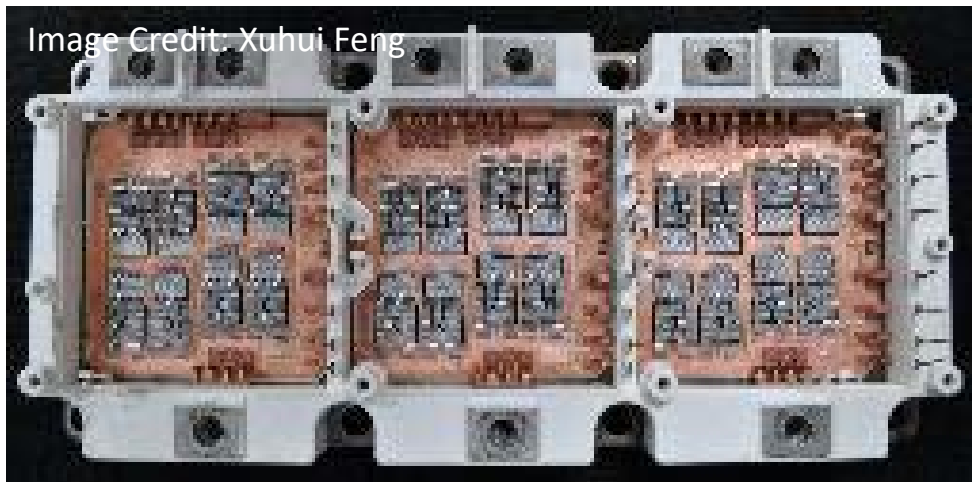
EESTT – Electrochemical Energy Storage Tech Team

GITT – Grid Interaction Tech Team

Power Electronics Package



Traditional Power Electronics Package



2015 BMW i-3

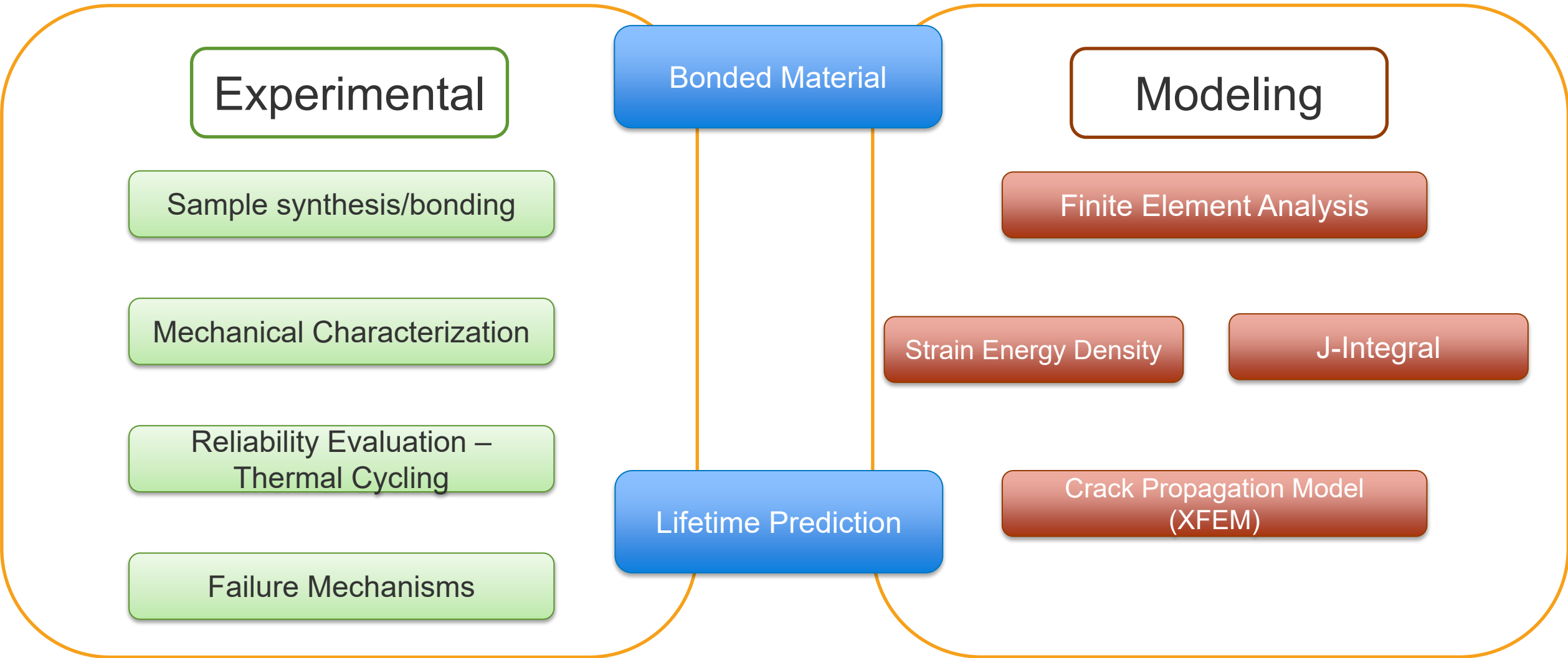


Cree Wide Bandgap Device Package



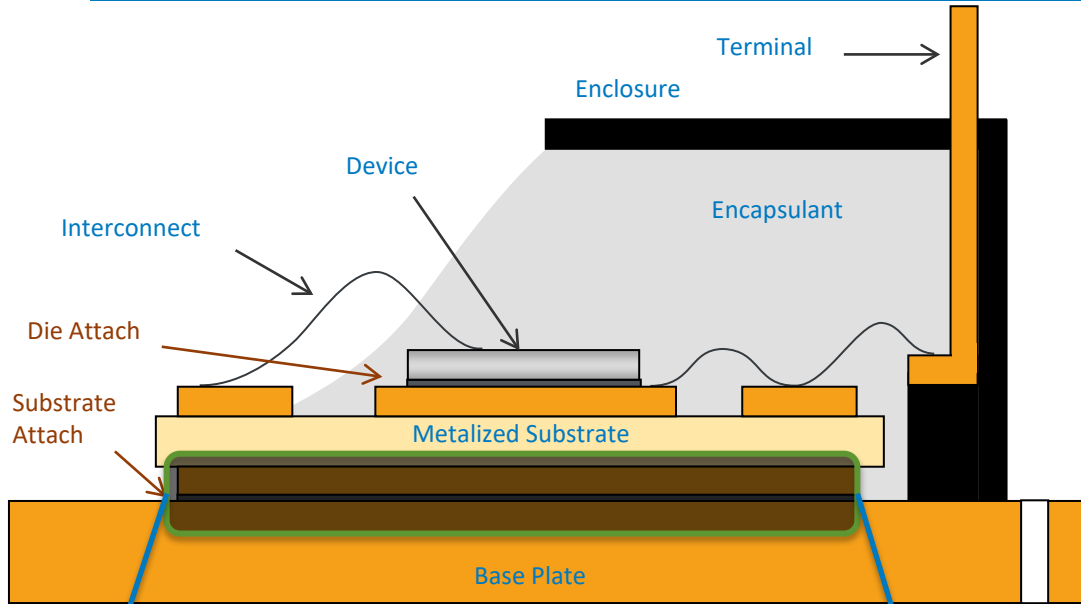
2012 Nissan Leaf

General Approach



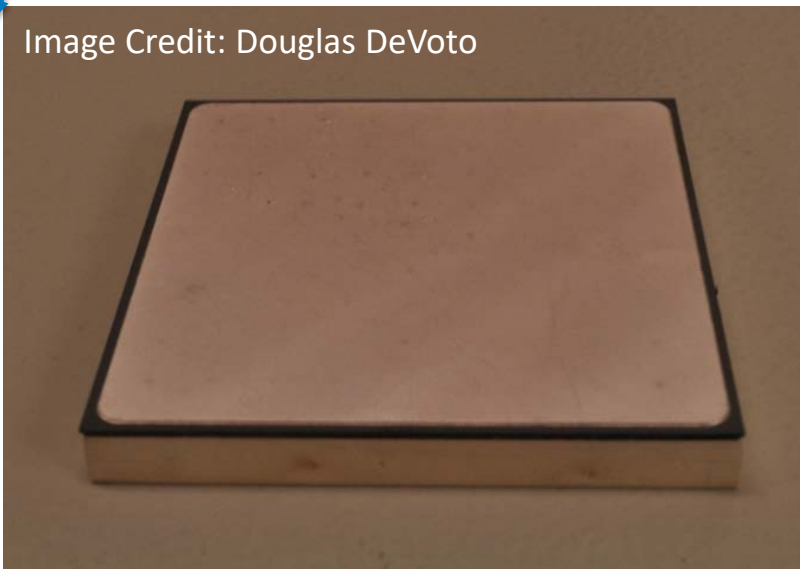
Bonded Interfaces at 150°C

Bonded Materials



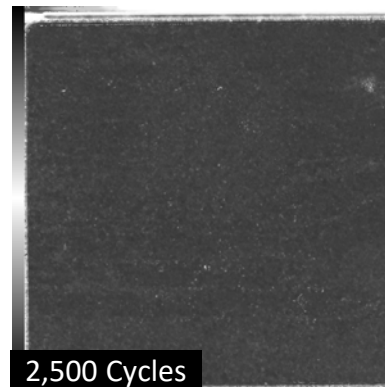
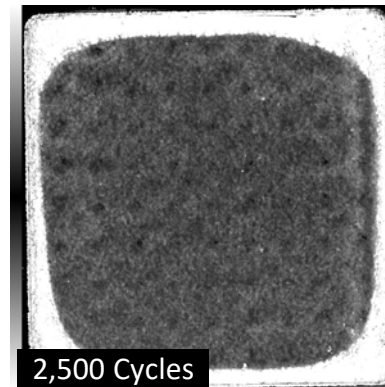
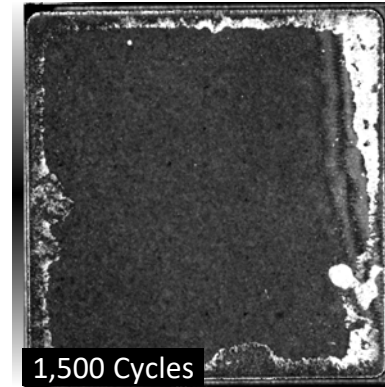
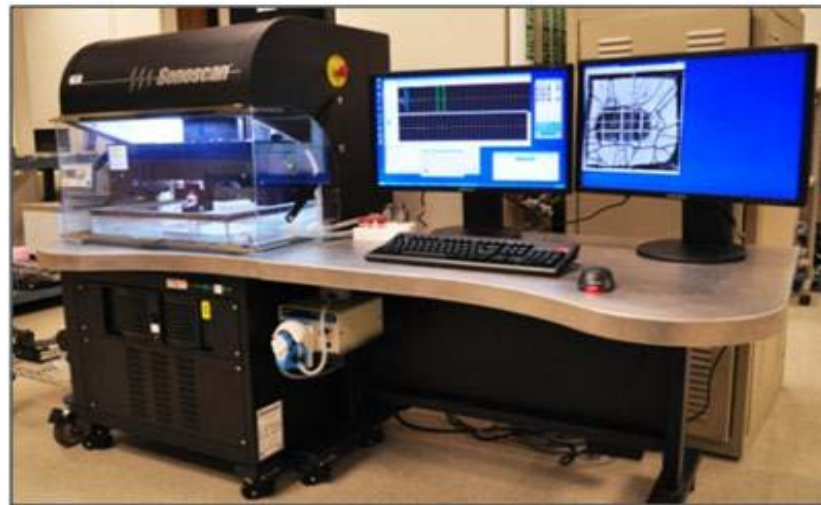
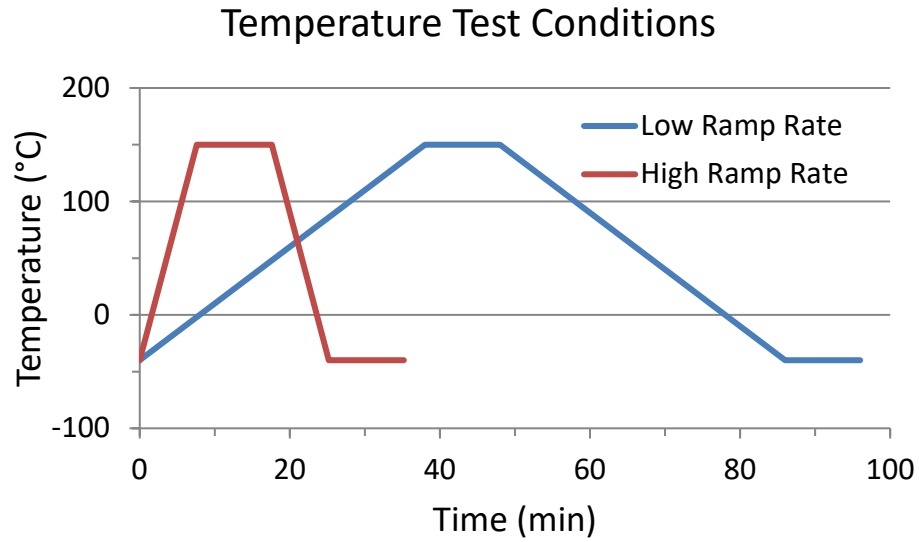
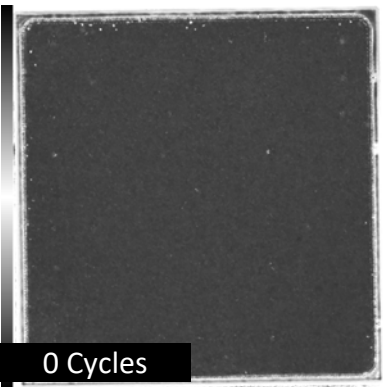
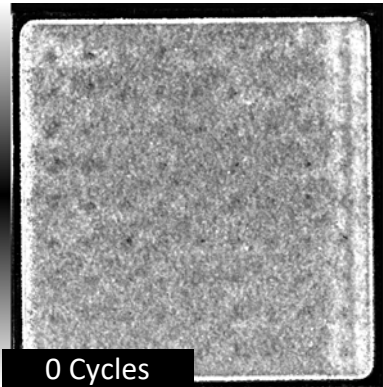
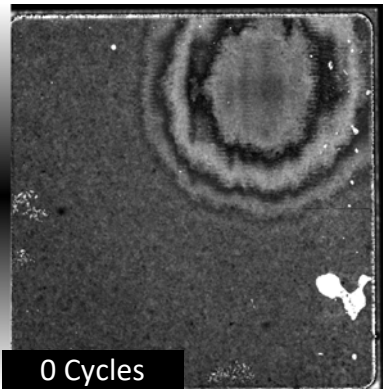
- Five samples of each bonded material were synthesized for characterization and included:
 - Silver plating on the substrate and base plate.
 - Substrate based on a Si_3N_4 active metal bonding process.
 - An interface between 50.8-mm x 50.8-mm footprint.

Image Credit: Douglas DeVoto



Bond Material Type	Name	Comments
Solder	Kester Sn63Pb37	Baseline (lead-based solder)
Sintered Silver	Semikron	Based on Semikron synthesis process
Adhesive	Btech HM-2	Thermoplastic (polyamide) film with embedded carbon fibers

Material Evaluation

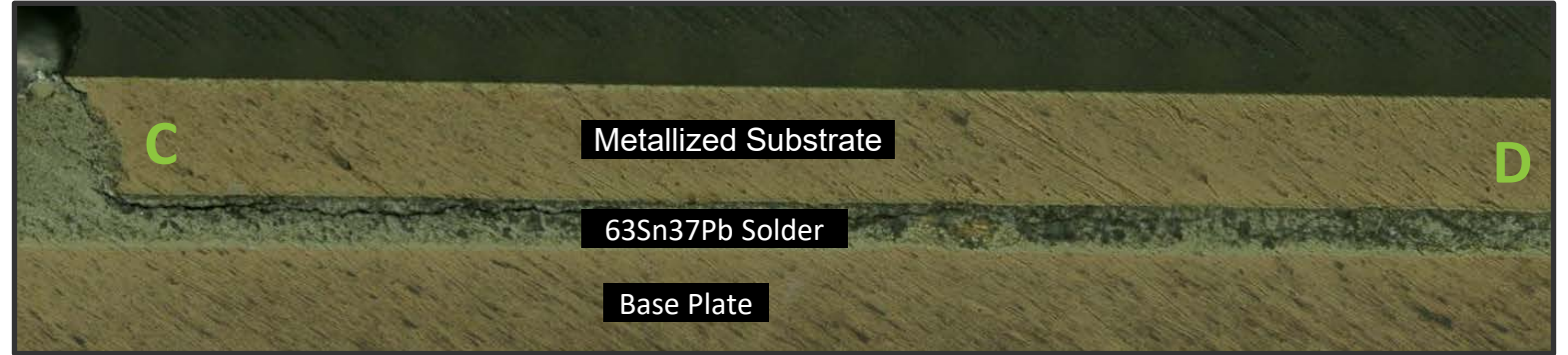
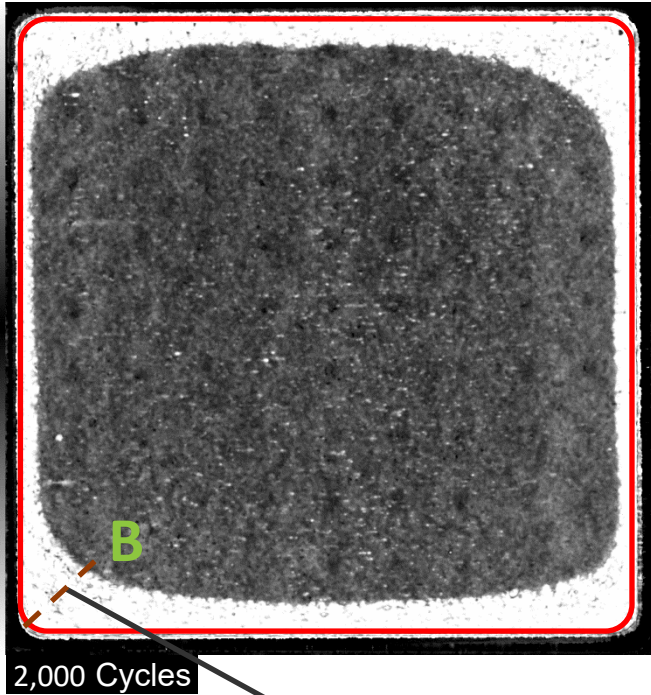


63Sn37Pb

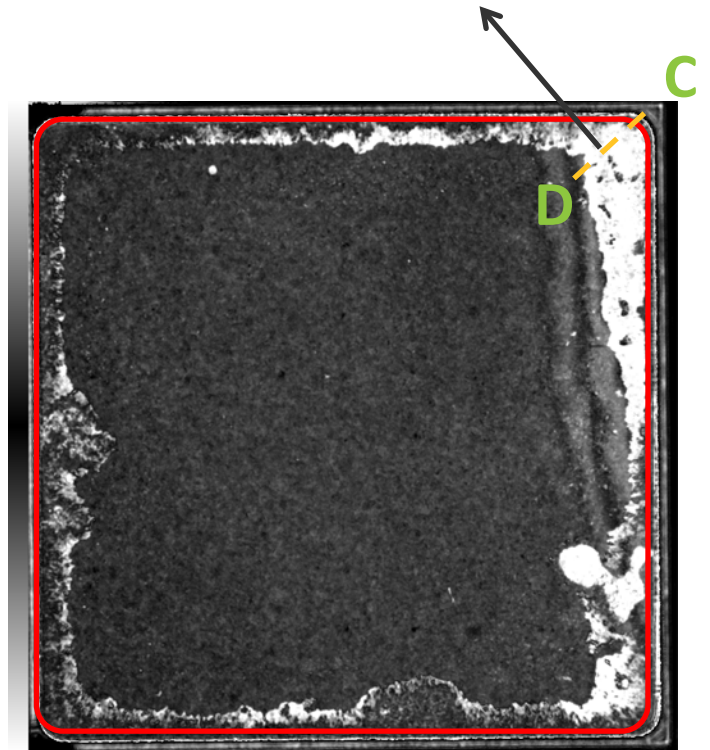
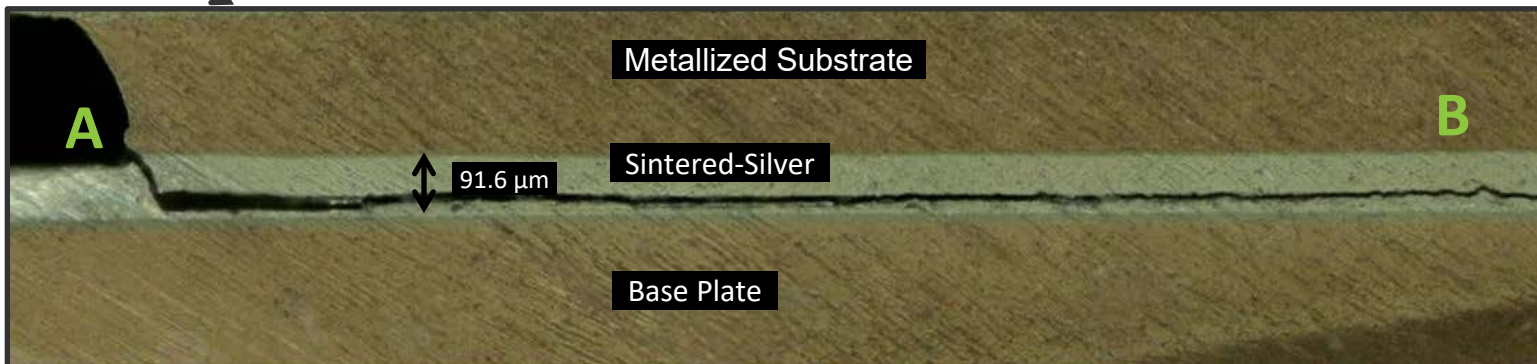
Sintered silver

Btech HM-2

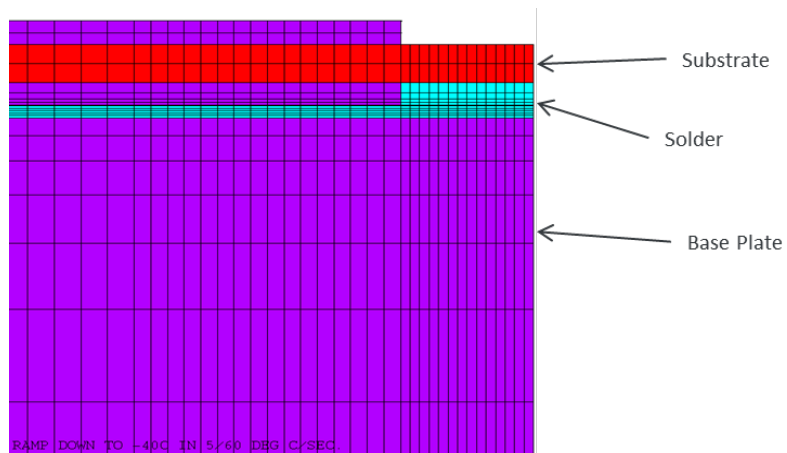
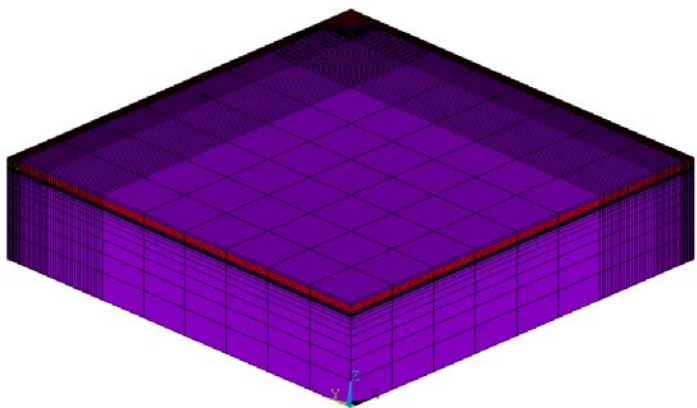
Failure Mechanisms



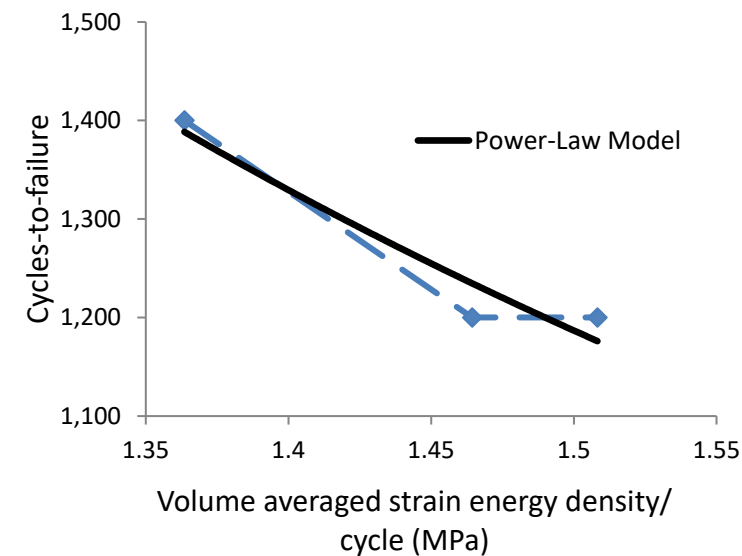
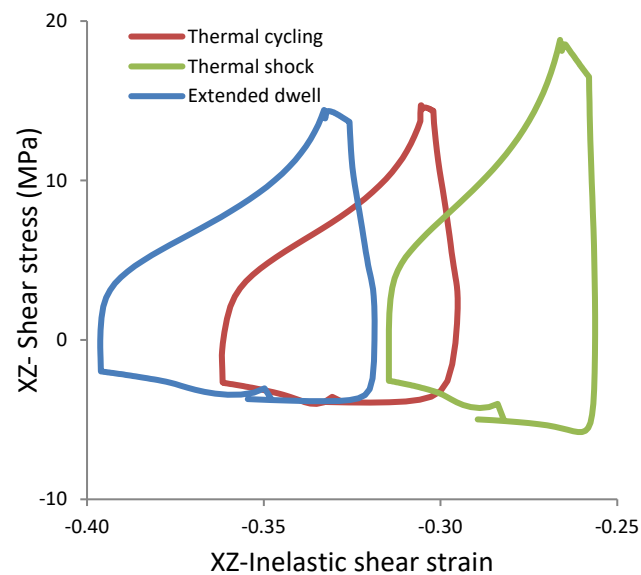
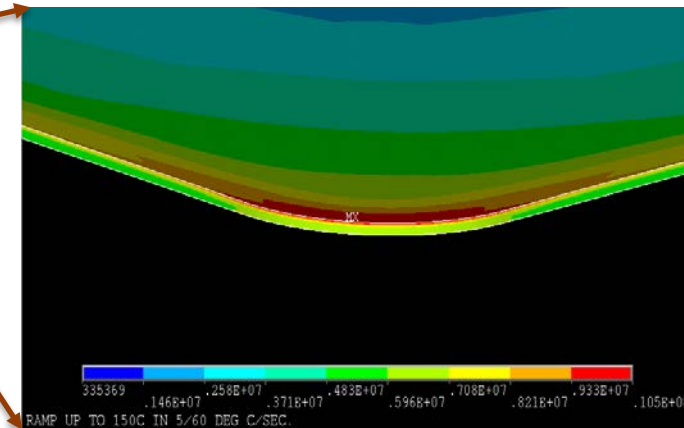
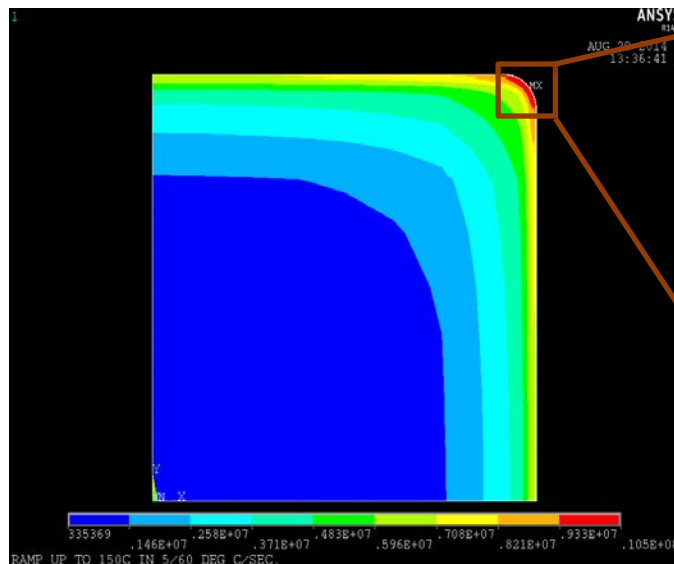
- Cohesive fracture observed in both solder and sintered silver.
- Failure criterion is 20% of crack growth by area.



Thermomechanical Modeling



- Anand viscoplasticity model applied to the solder layer.
- Thermal cycling load is the boundary condition.



Bonded Interfaces at 200°C

High-Temperature Materials

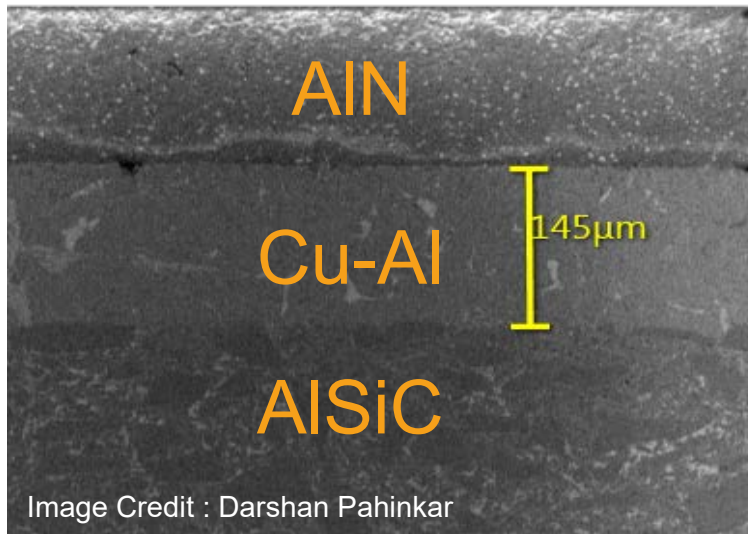
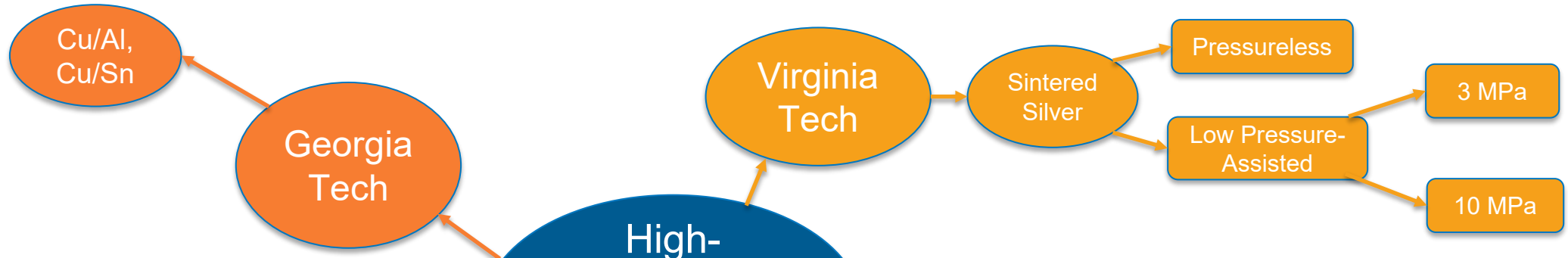


Image Credit : Darshan Pahinkar

Cu-Al bond – SEM image

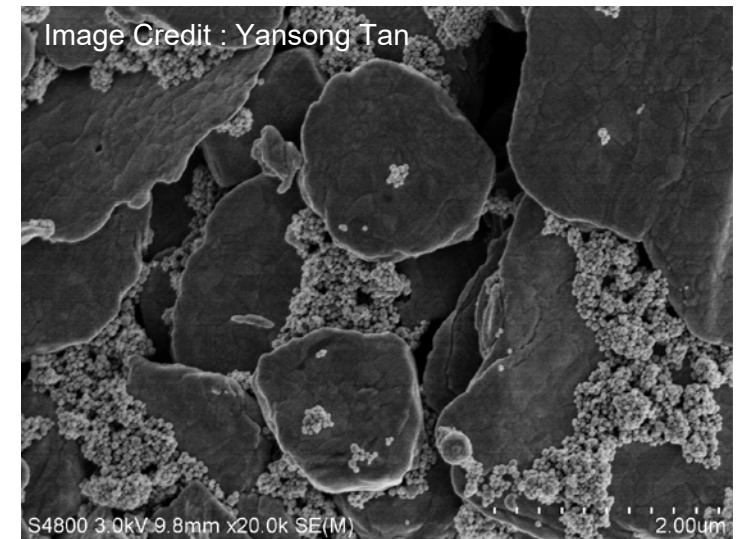


Image Credit : Yansong Tan

Hybrid-silver – SEM image

High-Temperature Bonded Material

NREL

Sintered Silver (industry)

Pressureless

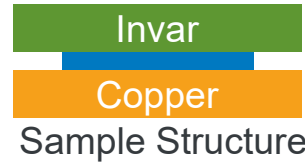
Cu: Copper
 Al: Aluminum
 Sn: Tin
 AlN: Aluminum Nitride
 AlSiC: Aluminum Silicon-Carbide

Approach – Reliability Evaluation



Image Credit: Douglas DeVoto

ϕ1-inch Copper and Invar Coupons: non-plated (top), plated with 5-μm-thick silver (bottom)



Samples with three different bond diameters were fabricated: 22 mm (left), 16 mm (center), and 10 mm (right)

Accelerated Thermal Cycling

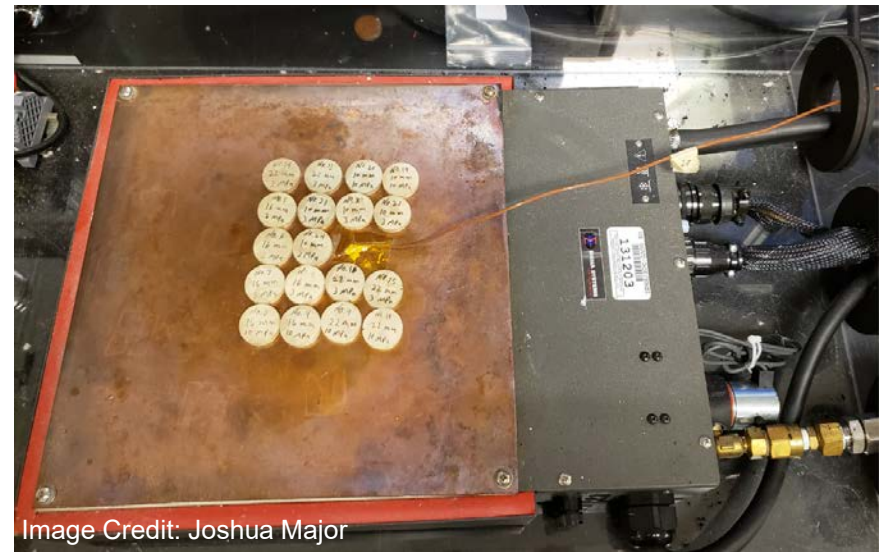
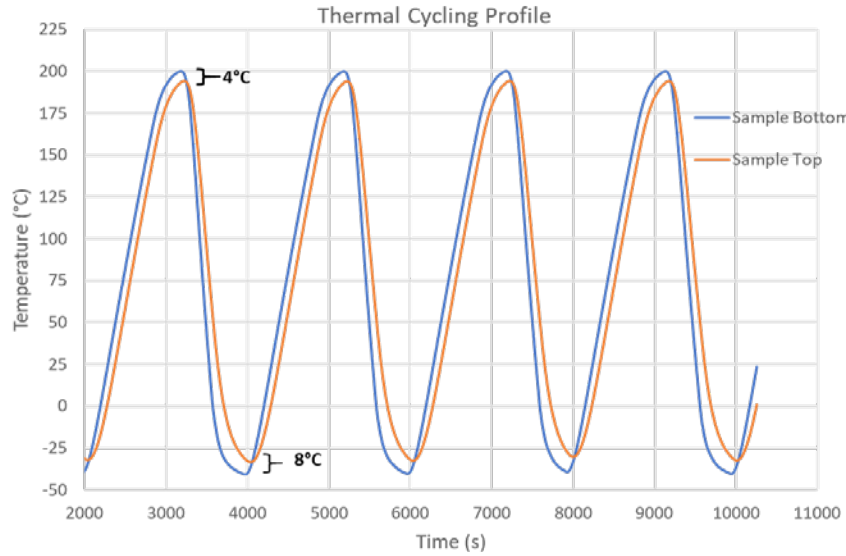
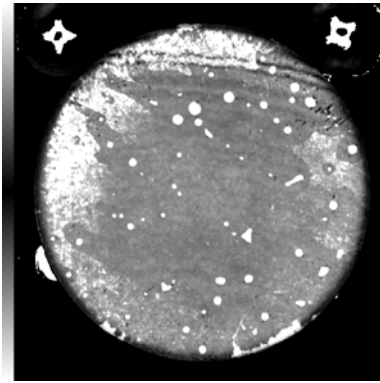
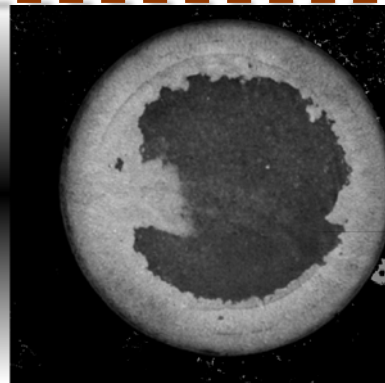
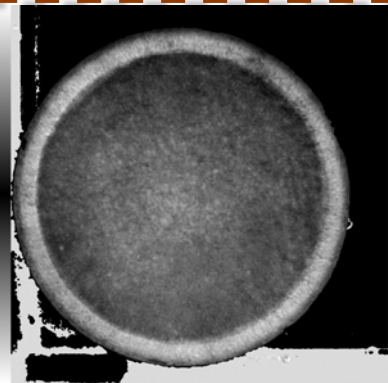


Image Credit: Joshua Major

Samples placed on thermal platform for thermal cycling, C-SAM images of these samples are taken periodically

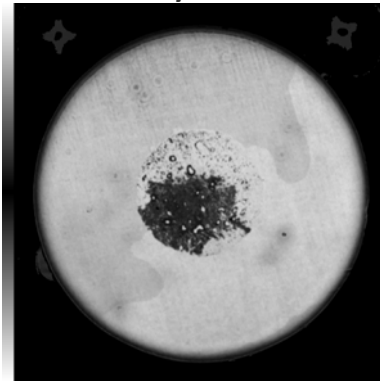
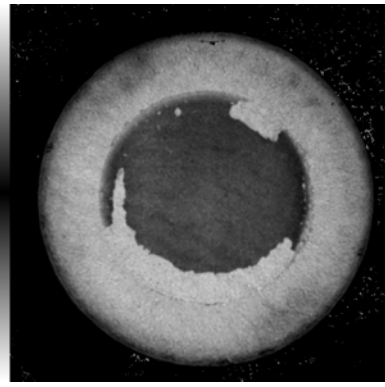
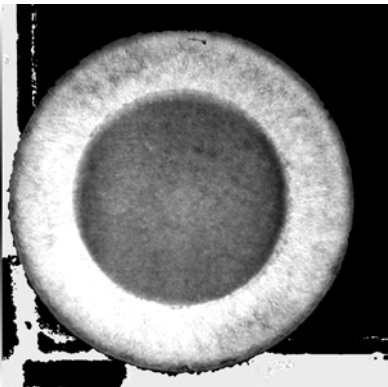
Reliability Comparison – Sintered Silver and Solder

φ 22 mm



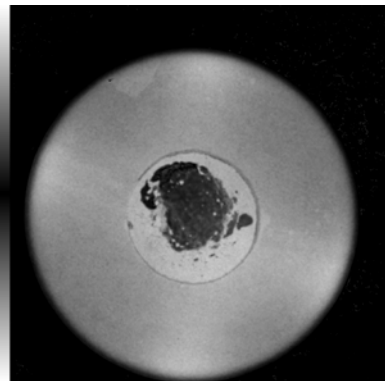
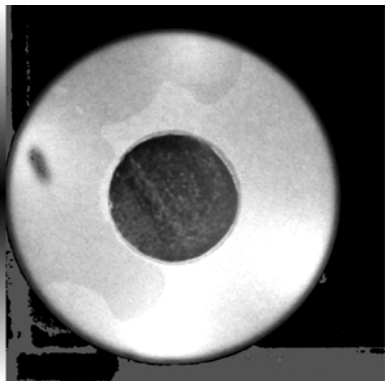
0 cycles

φ 16 mm



50 cycles

φ 10 mm

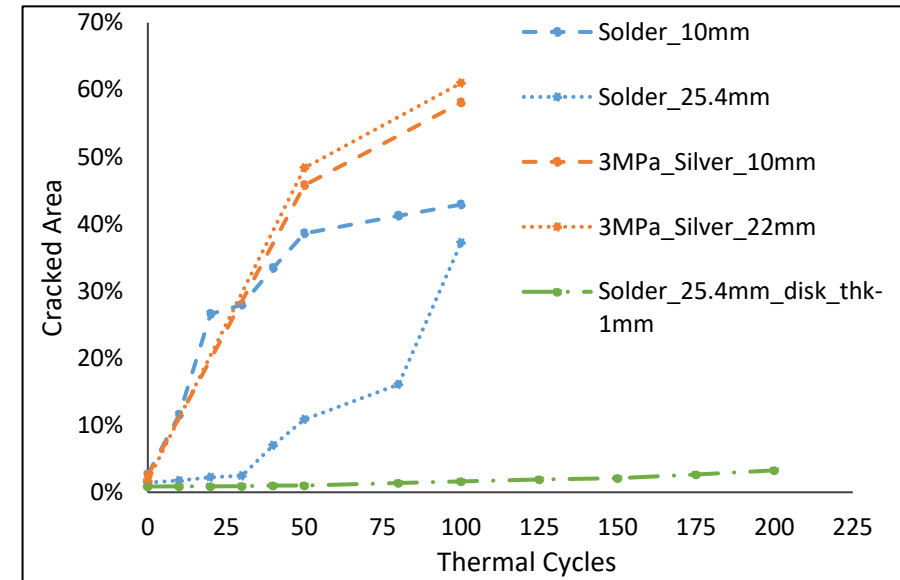
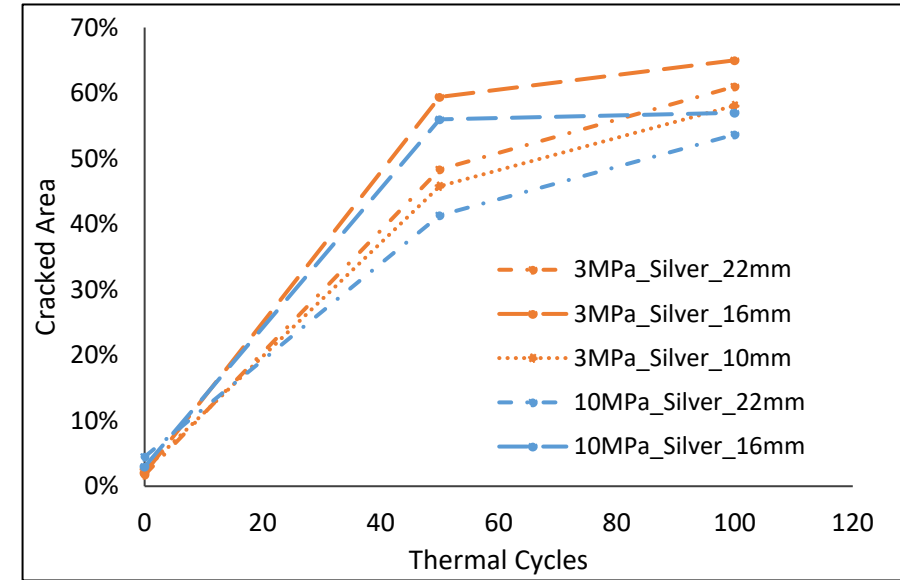


Sintered silver

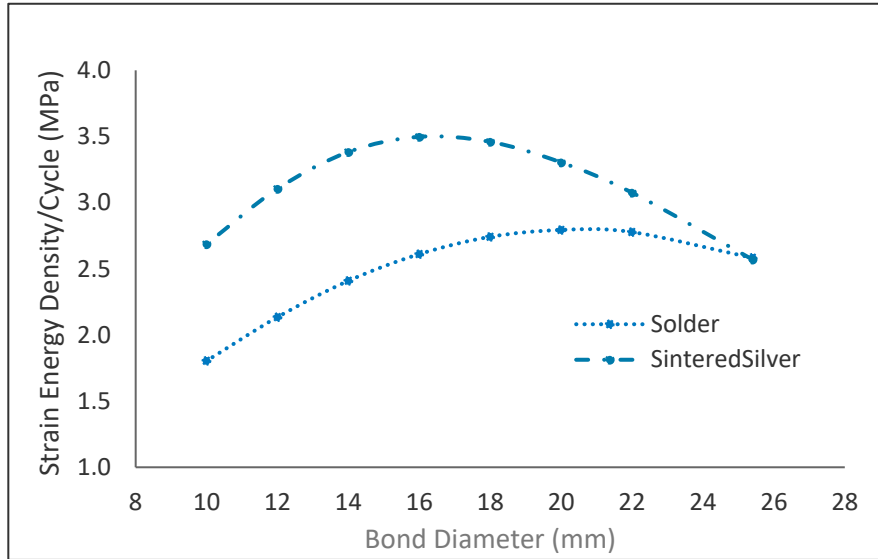
0 cycles

50 cycles

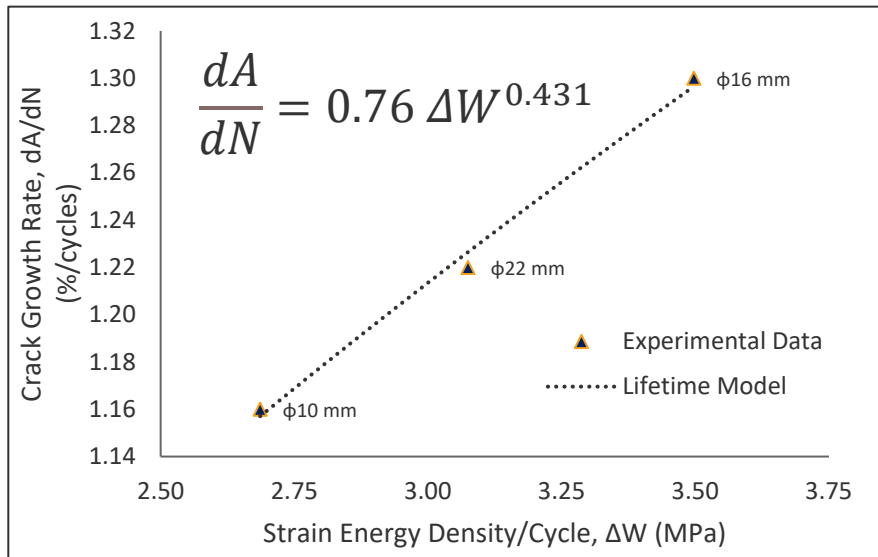
95Pb5Sn



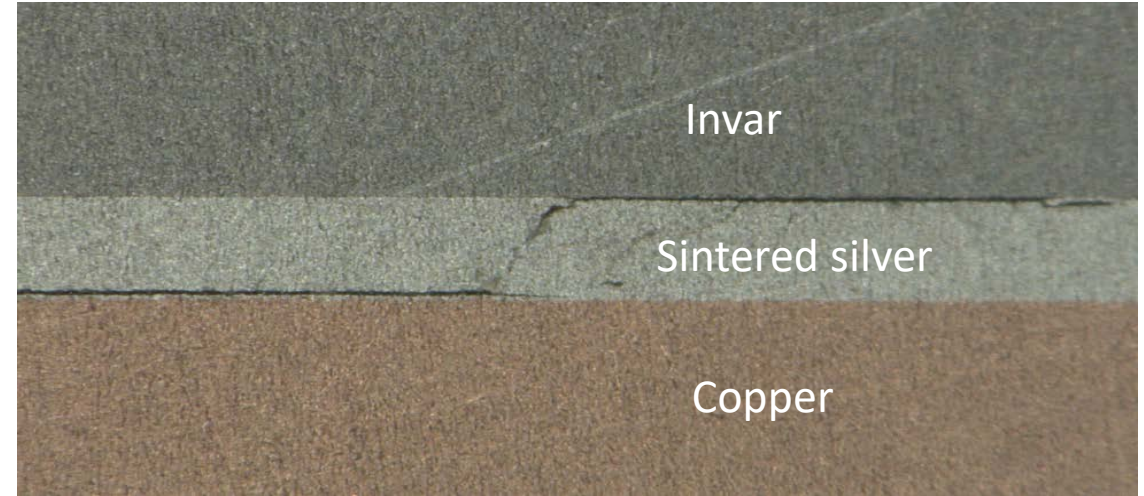
Lifetime Prediction Model



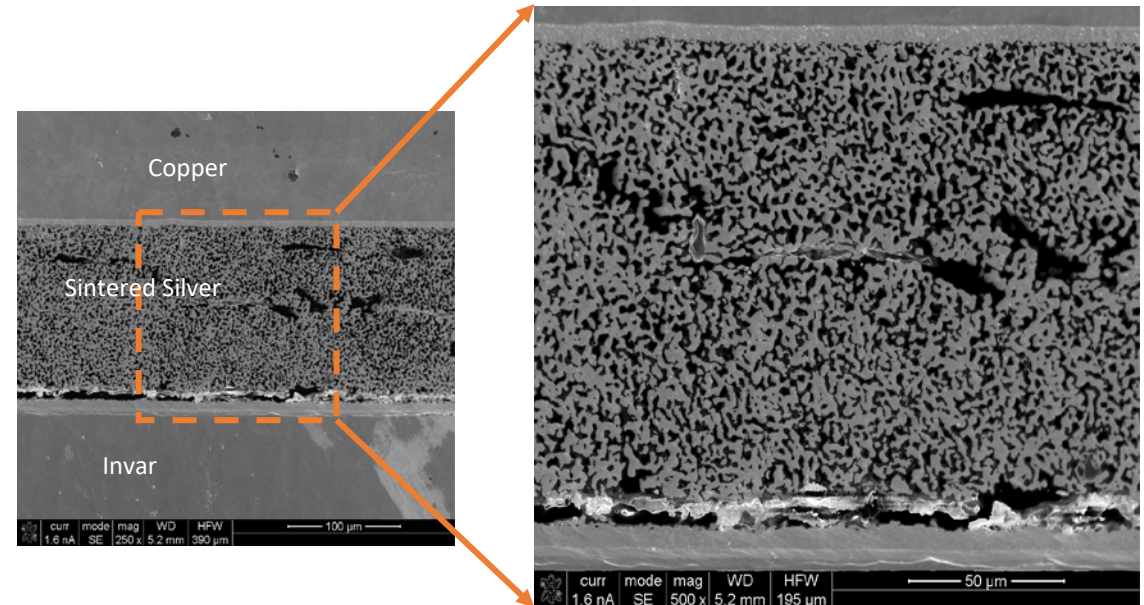
Modeling Results



Lifetime Prediction Model



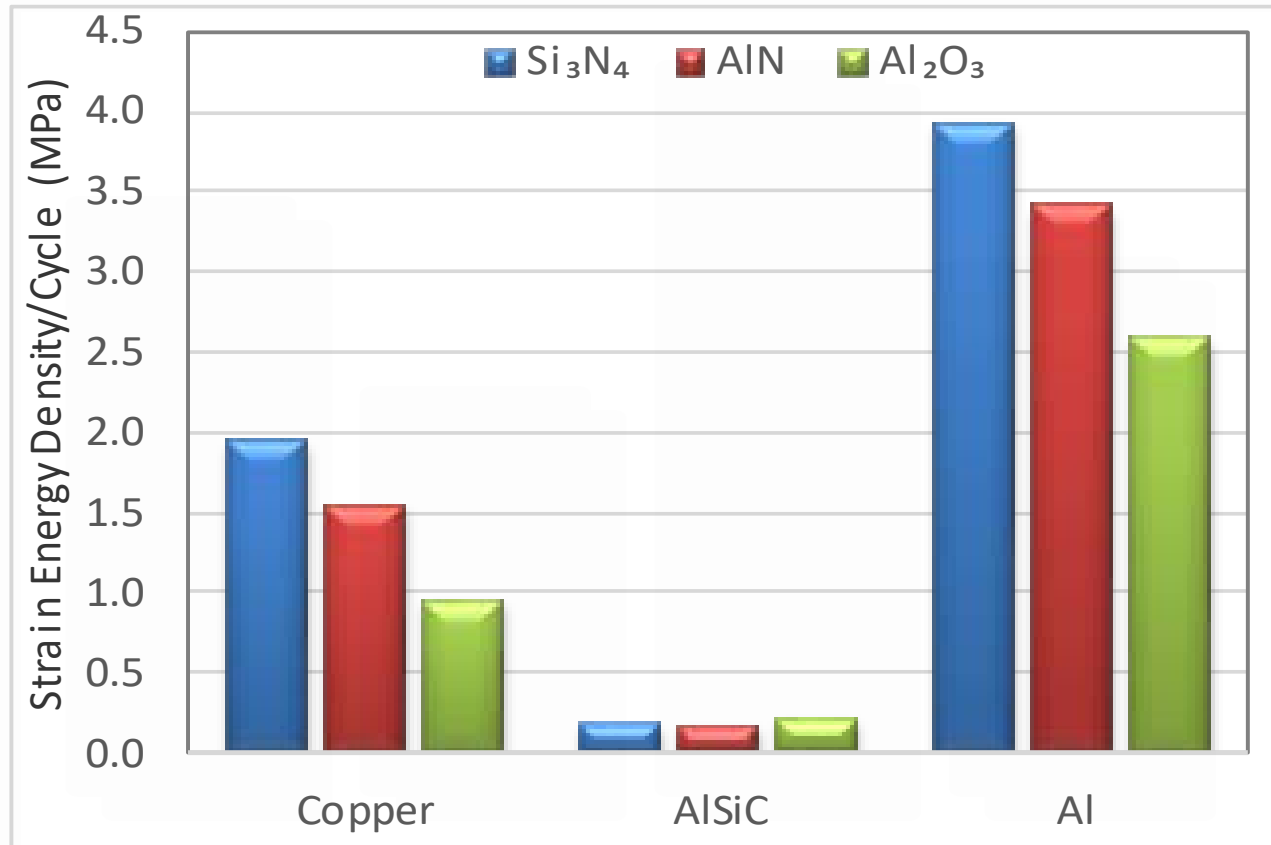
Optical Microscope Image



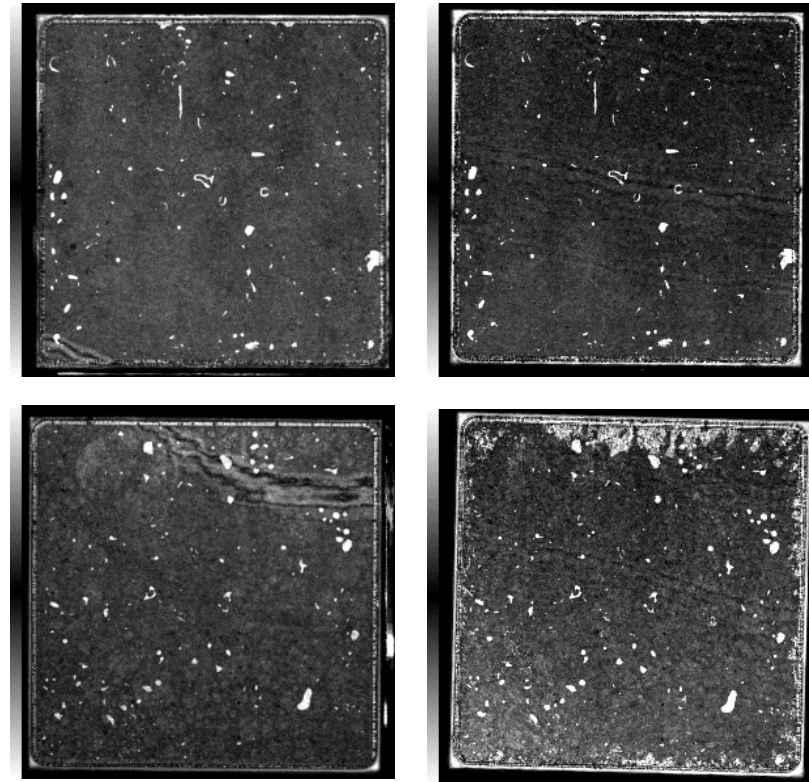
Scanning Electron Microscope Image

Thermomechanical Modeling – Parametric Study

Impact of Baseplate & Ceramic Material



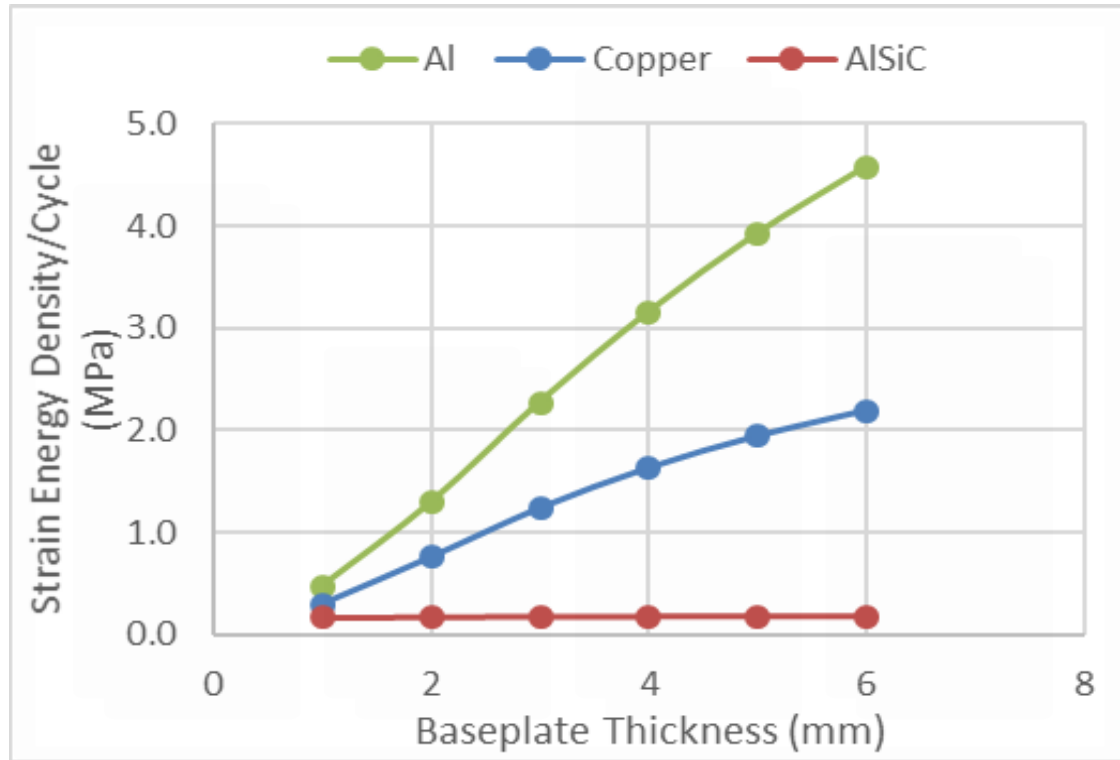
Thickness of baseplate – 5 mm; ceramic – 0.32 mm, metallization – 0.2 mm



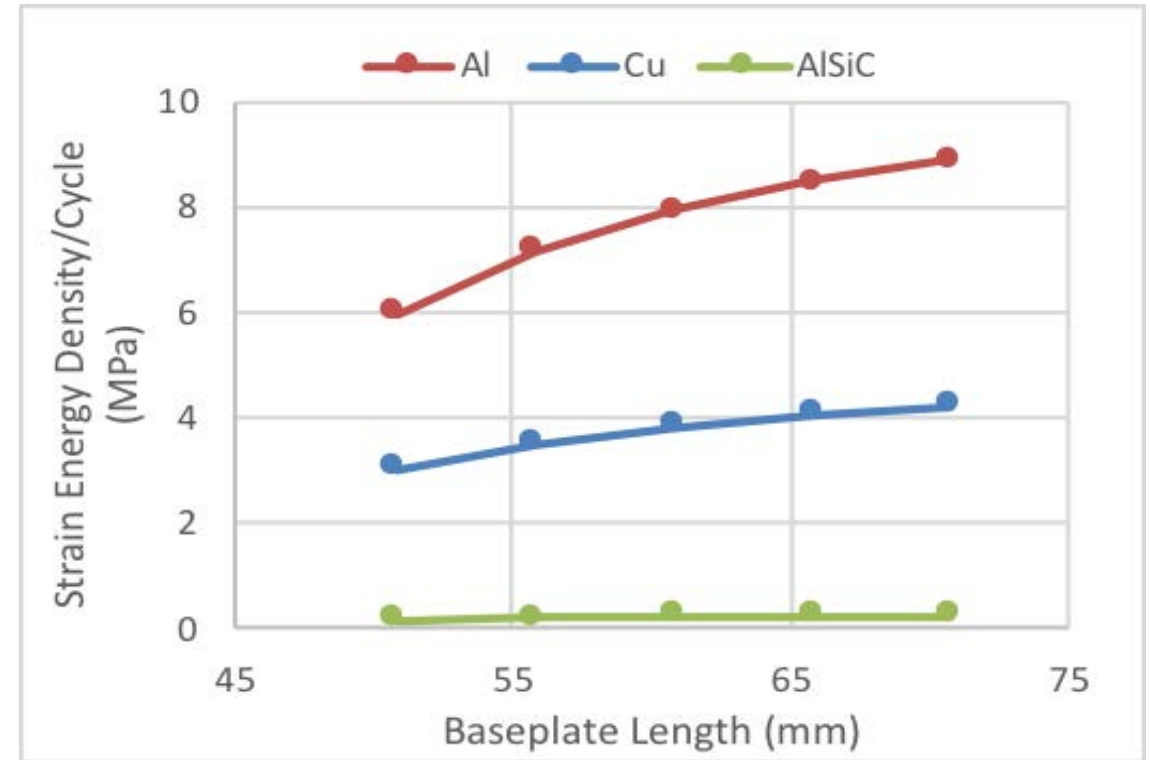
C-SAM Images of SAC305 solder with AlSiC (top) and Cu (bottom) baseplates. Images on the left and right were taken at 0 cycles and 500 cycles, respectively.

- AlSiC baseplate offers superior reliability than its Cu or Al counterparts, mainly due to the low coefficient of thermal expansion mismatch with the ceramic material.

Impact of Baseplate Thickness & Footprint



Ceramic (Si_3N_4) thickness – 0.32 mm; metallization – 0.2 mm

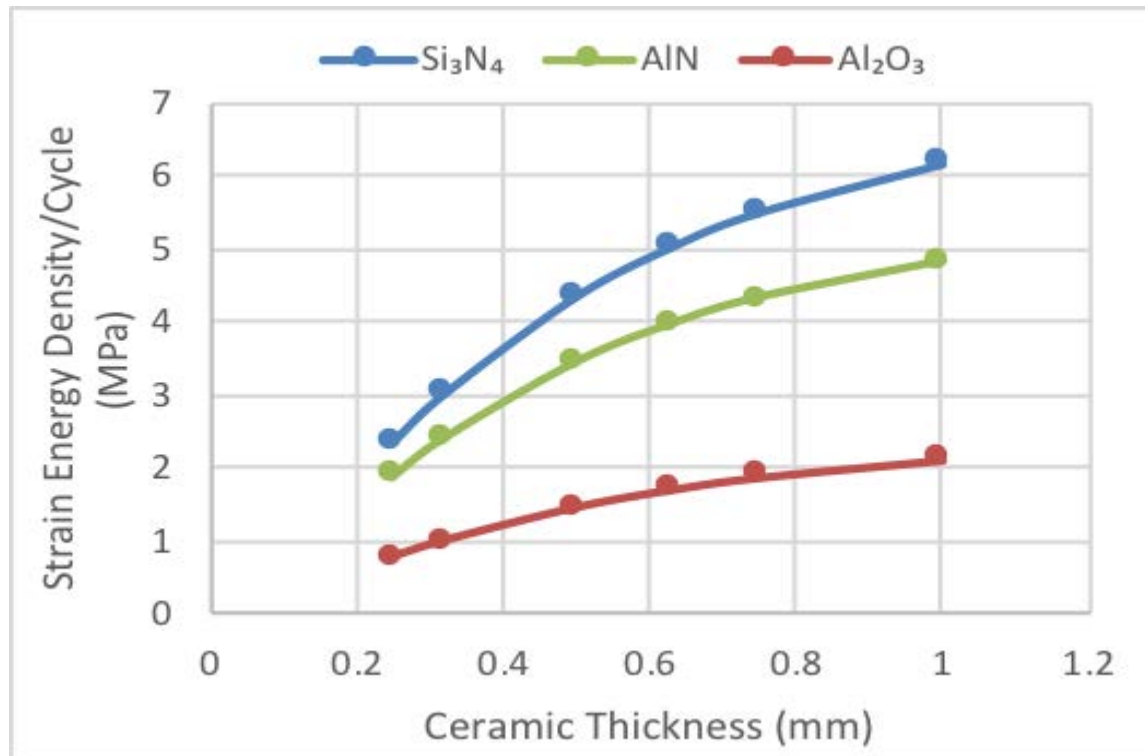


Baseplate thickness – 5mm; ceramic (Si_3N_4) – 0.32 mm; metallization – 0.2 mm.

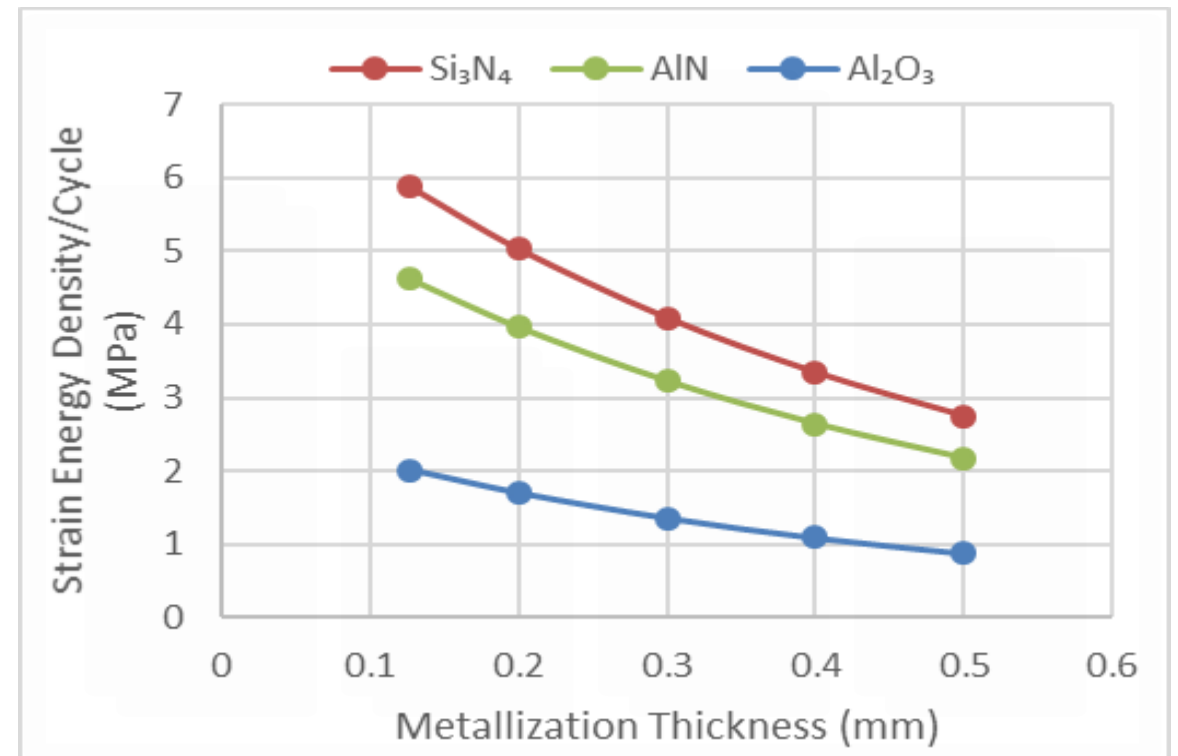
Thermal cycling profile - -40°C - 200°C

- Thickness variation has a larger impact on solder joint reliability than footprint/size variation.

Impact of Ceramic and Metallization Thickness



Baseplate (Cu) thickness – 5 mm; metallization – 0.2 mm



Baseplate (Cu) thickness – 5 mm; ceramic – 0.63 mm

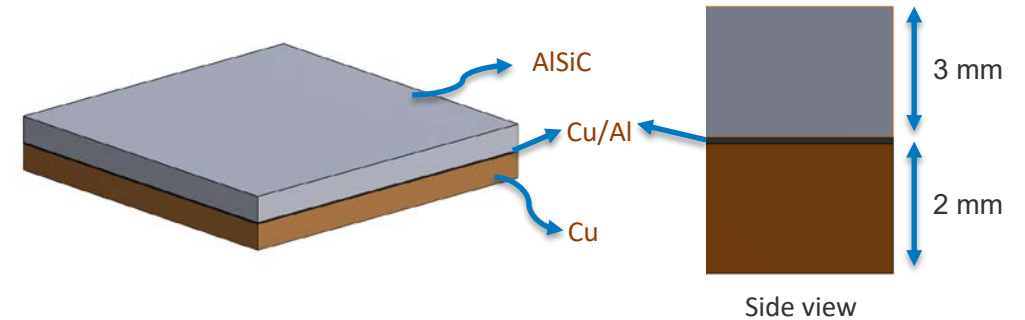
- Higher the coefficient of thermal expansion mismatch, higher the impact of stiffness variation is.

Other Work

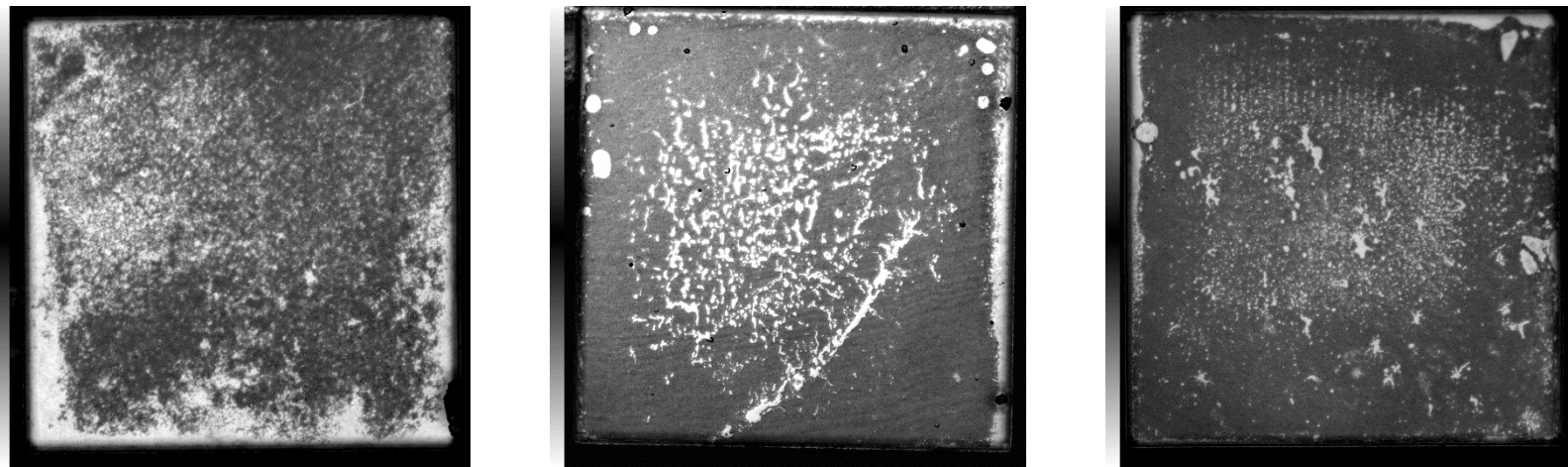
Transient Liquid Phase Cu-Al Bonds

- Reliability Evaluation

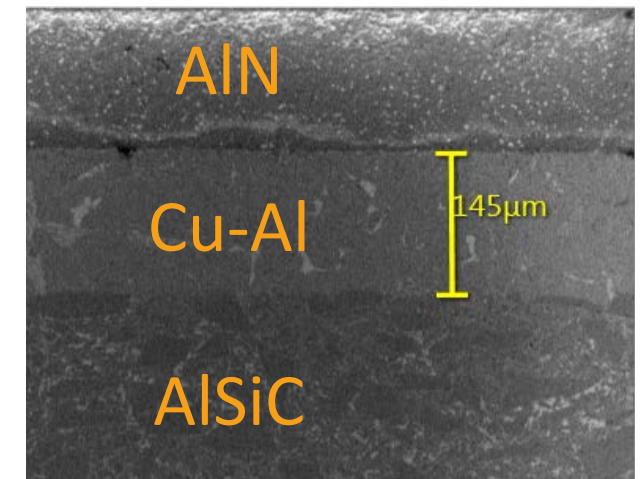
- Selected sample configuration: Cu bonded to AlSiC coupons using Cu-Al alloy, footprint is 1-inch x 1-inch.
- Samples synthesized at Georgia Tech and sent to NREL for thermal cycling experiments.
- Thermal cycling currently underway; scanning acoustic microscope images and thermal resistance measurements are indicators of thermomechanical performance.



Sample design for reliability evaluation



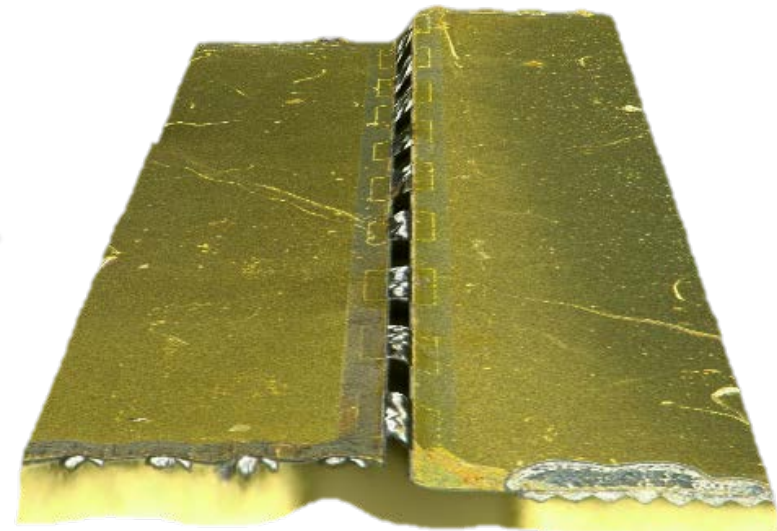
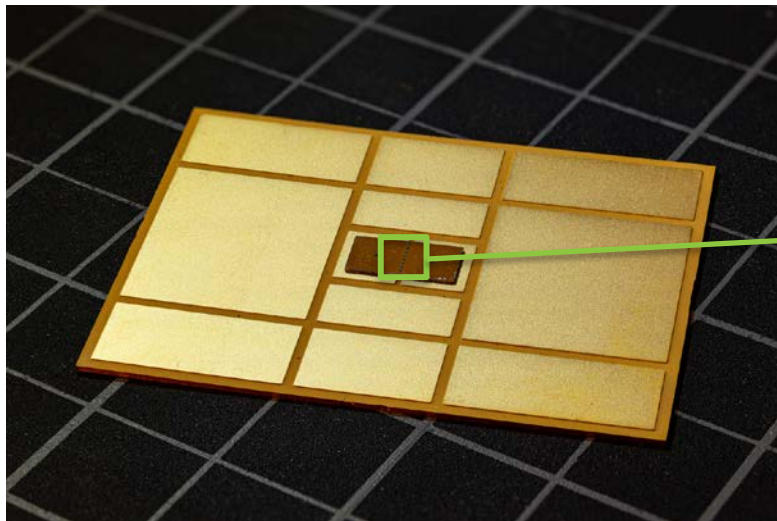
C-SAM images of AlN-AlSiC sample with Cu-Al bond



Cross-sectional SEM image of Cu-Al bond

Organic DBC and Quilt Packaging

- Alternative interconnect designs are required as devices are reduced in size and spacing between devices is minimized
- **Traditional wire interconnects or etched substrates for topside electrical connections will be replaced with direct chip-to-chip connection**
- Devices are joined with quilt packaging, eliminating the need for wire bonds or other external electrical connection technology
 - Experimental samples have been designed in collaboration with IIC and ORNL
 - Reliability evaluation will be completed at NREL



Challenges and Opportunities

- Material development
 - Reliable, cost-effective, thermally and electrically high-performing
 - Data-driven techniques to identify material compositions
 - Functionally graded materials
 - Constitutive models.
- Faster characterization techniques
 - Time-independent evaluation of material/package
 - Combining different physics-based characterization for co-designed packages
- Circular economy design principles
 - Recycling of non-failed components.

Reference Material

- Top causes of failure in power semiconductors - <https://chargedevs.com/features/top-causes-of-failure-in-power-semiconductors/>
- Here's why Tesla transitioned to a semi-custom power module design in Model 3 inverter - <https://chargedevs.com/features/heres-why-tesla-transitioned-to-a-semi-custom-power-module-design-in-model-3-inverter/>
- Reliability challenges of automotive power electronics – U. Scheuermann
– <https://doi.org/10.1016/j.microrel.2009.06.045>
- Power Electronics Reliability: State of the Art and Outlook – H. Wang
– <https://doi.org/10.1109/JESTPE.2020.3037161>

Summary

- Reliability evaluation of bonded materials is a critical research area for enabling low-cost, lightweight, and reliable power electronic packages that can operate at high temperatures.
- Synthesis of high-temperature bond materials, mechanical characterization, reliability evaluation, thermomechanical modeling, and lifetime prediction models.
- Collaborations – Virginia Tech, Georgia Tech, Oak Ridge National Laboratory, Ames National Laboratory, Sandia National Laboratory.
- Publications:
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Thank You

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